## N tic fR ferenc s Cited

Application/Control No.
09/539,624
Examiner

Applicant(s)/Patent Under Reexamination COFFMAN ET AL.

Examiner Art Unit
Syed J Ali 2127

Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,421,742 B1	07-2002	Tilliar, Fabian S.	710/1
	В	US-5,319,782 A	06-1994	Goldberg et al.	709/104
٢	С	US-6,243,107 B1	06-2001	Valtin et al.	345/506
	۵	US-4,435,766	03-1984	Haber et al.	710/200
	E	US-6,463,527 B1	10-2002	Vishkin, Uzi Y.	712/245
	F	US-5,835,763 A	11-1998	Klein, Paul F.	709/101
	Ø	US-6,466,898 B1	10-2002	Chan, Terence	703/17
	Ή	US-6,026,427 A	02-2000	Nishihara et al.	709/106
	_	US-6,035,321 A	03-2000	Mays, Richard Chapman	709/103
	7	US-6,134,579 A	10-2000	Tavallaei et al.	709/100
	К	US-6,272,625 B1	08-2001	deCarmo, Linden A.	712/245
	L	US-			
$\sqcap$	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	P					
	Ø					
	R					
	s					
	Т					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.